

Spec	cification for Approval
	Date: 2024/1/1
	Customer:
	BYTEK P/N: BAM1210NF-900T01
	CUSTOMER P/N:
	DESCRIPTION:
	QUANTITY: pcs
REM	ARK:
	Customer Approval Feedback
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BAM1210NF-900T01

1. Scope

This specification applies to Multilayer Common Mode Choke Coil, BAM Series Its Application is limited for the High speed differential transmission line like as followings. USB, LVDS, MIPI, MDDI, MHL, HDMI, DVI.



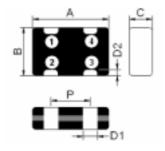
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Certificate GreenPartner

2. Dimensions



Chip Size						
Size	Α	В	С	Р	D1	D2
1210	1.25±0.15	1.0±0.15	0.55 ±0.10	0.55±0.10	0.30±0.10	0.25+0.15/-0.1

3

Units: mm

3. Part Numbering

BAM	1210	NF	-	900		<mark>01</mark>
А	В	С		D	Е	F
A: Series						
B: Dimensi	on	AxB				
C: Material		Lead Free	e Code			
D: Impedar	nce	Common	Mode	Impedance	900=90)
				=		

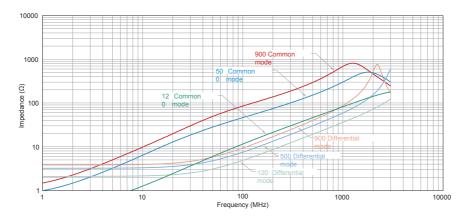
E: Packaging T=Taping and Reel , B=Bulk(Bags)

F: Explain

4. Specification

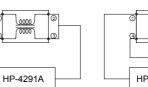
	Common Mode Impedance ()	Test Frequency (MHz)	Rated Voltage (Vdc) max.	Insulation Resistance (M) min.	DC Resistance () max.	Rated Current (mA) max.
BAM1210NF-900T01	90±25%	100	5	10	3.0	100

Impedance-Frequency Characteristics





Normal-mode (Differential-mode)





P1

5. Reliability and Test Condition

Item	Performance			Test Condition			
Series No.		BAM					
Operating Temperature	-40~+85 (Including self-generated heat)						
Transportation Storage Temperature		-40~+85		For long Application	•	nditions, p	lease see the
Impedance (Z)					quipment:42 g: 16192A (
Insulation Resistance	-			Measuring p	oints: 1 to 2 oltage: Rate	or 3 to 4	,
DC Resistance	Within the specified toleran	ce		-	points: 1 to	Ť	o 4
Rated Current	-						
	Per table 1. Table 1						st board and the conditions shown
	Appearance	No remarkable Defect	_	Vibraiton range	frequency	10Hz	to 55Hz
Vibration	Commom Impedance change	Within±20%		Overall a	amplitude		5mm
	rate Insulation resistance	100mΩ min		<u>1 cycle</u> Time		1min.(10 X Y Z	55 10Hz) 2 hours each
Solderability	More than 75% of terminal	electrode shall be covered	with fresh solder.	visually chec The speed f mm/s. <u>Table 3</u> <u>Solder te</u> <u>Immersio</u>	test samples cked. for immersion emperature on time	n and taking	taken out and g out shall be 25 15 ±3 4s±1s
Resistance to Soldering Heat	Per table 1.			after immer conditions s After this, measured a hours.(Note	sed into flux hown in Tabl test samples fter kept at r 1)	and preh e 4. s shall be oom tempe	to molten solder eated under the taken out and rrature for 2 to 3 ing out shall be
				Preheatin Resistan Soldering	ice to g Heat		0 , 3min. 60 ±5 0s±0.5s
				Steps 1 to repeated 5 t After the te temperature	4 shown in T imes. est, keep the	able 5 as o test sam al humidity	ne cycle shall be ple at a normal for 2 to 2 hours,
Thermal Shock	Per table 1.			Step 1	Temperatur		ration (min)
				2	-40 +0/- Normal te	emp	30±3 2~3
				<u>3</u> 4	+85 +3/- Normal te		30±3 2~3
Resistance to Humidity	Per table 1.			temperature 90% to 95% After the te	of 40 ± 2 for 500+24/- st, keep the with a norm	and rela 0 hours. e test sam al humidity	mo hygrostat at tive humidity of ple at a normal for 2 to 3 hours, ed.(Note 1)
High Temperature Load Life Test	Per table 1.			temperature supplying 1 After the te temperature	of 85 ±2 to 2 and st, keep the	for 500+2 3 - 4 with test sam al humidity	ostatic oven with 4/-0 hours while rated current. ple at a normal for 2 to 3 hours, ted.(Note 1)

Item	Performance	Test Condition
High Temperature Life Test	Per table 1.	Test board shall be kept in an atmosphere with temperature of 85 ±2 for 500+24/-0 hours. After the test, keep the test sample at a normal temperature with a normal humidity for 2 to 3 hours, then measurement shall be conducted.(Note 1)
	Appearance: No mechanical damage.	Warp : 2mm(1210),1mm(0806) Testing board : Glass epoxy-resin substrate Thickness : 0.8mm

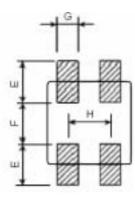
(Note 1) If guestion is found in the result of measurement, another measurement shall be conducted after test samples shall be kept for 48+/-2 hours.

6. Soldering and Mounting

6-1. Recommended PC Board Pattern

	Chip Size							terns Fo oldering	-
Туре	Α	В	С	D1	D2	Е	F	G	н
0806	0.85±0.05	0.65±0.05	0.40 ±0.05	0.27±0.10	0.20+0.05/-0.1	0.25~0.35	0.25~0.35	0.25~0.35	0.5
1210	1.25±0.15	1.0±0.15	0.55 ±0.10	0.30±0.10	0.25+0.15/-0.1	0.45~0.55	0.7~0.8	0.25~0.35	0.55

Units: mm



PC board should be designed so that products can prevent damage from mechanical stress when warping the board.

Products shall be positioned in the sideway direction against the mechanical stress to prevent failure.

6-2. Soldering

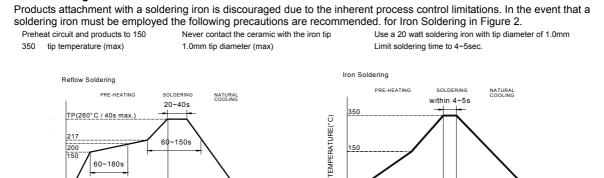
Mildly activated rosin fluxes are preferred. The terminations are suitable for re-flow soldering systems. If hand soldering cannot be avoided, the preferred technique is the utilization of hot air soldering tools. Note.

If wave soldering is used ,there will be some risk.

Re-flow soldering temperatures below 240 degrees, there will be non-wetting risk

6-2.1 Lead Free Solder re-flow:

Recommended temperature profiles for lead free re-flow soldering in Figure 1.



Over 60s

TIME(sec.)

Iron Soldering times : 1 times max

Fig.2



25

Accordingly increasing the solder volume, the mechanical stress to product is also increased. Exceeding solder volume may cause the failure of mechanical or electrical performance. Solder shall be used not to be exceed as shown in right side:

Minimum fillet height = soldering thickness + 25% product height

TIME(sec.)

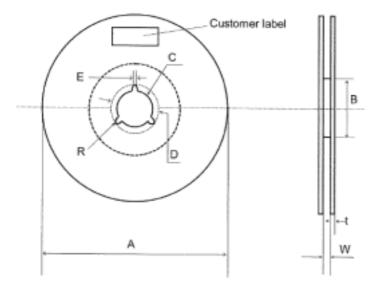
Reflow times: 3 times max Fig.1



60~180s

480s max

7-1. Reel Dimension



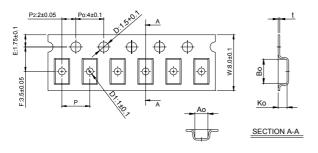
Code	Α	В	С	D	Е	w	t	R
Dimension	178±2.0	50 min	13±0.2	21±0.8	2.0±0.5	10±1.5	2.5 max	1.0

Units: mm



Gradual cooling

7-2. Tape Dimension (paper)



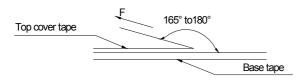
Series	Во	Ao	Ко	Р	t
0806	0.95±0.05	0.75±0.05	0.55±0.05	4.0±0.10	0.3 max
1210	1.40±0.05	1.15±0.05	0.65±0.05	4.0±0.10	0.3 max

Units: mm

7-3. Packaging Quantity

Chip size	0806	1210
Chip /Reel	10000	4000
Inner box	50000	20000
Middle box	250000	100000
Carton	500000	200000

7-4. Tearing Off Force



The force for tearing off cover tape is 15 to 60 grams in the arrow direction under the following conditions.

Room Temp.	Room Humidity	Room atm	Tearing Speed
()	(%)	(hPa)	mm/min
5~35	45~85	860~1060	300

Application Notice

Storage Conditions

- To maintain the solder ability of terminal electrodes:
- 1. BYTEK products meet IPC/JEDEC J-STD-020D standard-MSL, level 1.
- 2. Temperature and humidity conditions: Less than 40 and 60% RH.
- 3. Recommended products should be used within 12 months from the time of delivery.
- 4. The packaging material should be kept where no chlorine or sulfur exists in the air.

Transportation

- 1.Products should be handled with care to avoid damage or contamination from perspiration and skin oils.
- 2. The use of tweezers or vacuum pick up is strongly recommended for individual components.